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José Sasian
Richard N. Youngworth
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Introduction

The 2009 Optical System Alignment, Tolerancing, and Verification conference ended up being a turning point as the community showed a significant increase both in submitting papers and in attending the sessions. The audience made it obvious that the conference fills an important need and that the topics are current and useful.

The conference had a diverse mixture of papers covering a variety of interesting topics. Papers ranged from research through applications, indicating various stages of development of alignment, tolerancing, and verification in our discipline. One strong highlight of the conference was the series of James Webb Space Telescope (JWST) papers where expert authors showed the community JWST alignment plans and methodologies. These papers are very welcome and appreciated as they cover some of the very difficult challenges and solutions that program is producing. In addition to the offerings related to JWST, the conference had papers covering fundamental alignment aberrations and studies, papers related to tolerancing of various optical systems, and a host of papers showing advances in a number of applications.

We thank the authors for sharing their expertise, the audience for attending the conference, and SPIE for providing an excellent conference forum. We look forward to continuing this conference next year and making it as beneficial as possible for the optics and photonics community.

José Sasian
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